
**Vitreous and porcelain enamels —
Low-voltage test for detecting and
locating defects —**

**Part 1:
Swab test for non-profiled surfaces**

*Émaux vitrifiés — Essai à basse tension pour la détection et la
localisation des défauts —*

Partie 1: Essai avec tampon pour les surfaces non profilées





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ISO copyright office
CP 401 • Ch. de Blandonnet 8
CH-1214 Vernier, Geneva
Phone: +41 22 749 01 11
Fax: +41 22 749 09 47
Email: copyright@iso.org
Website: www.iso.org

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